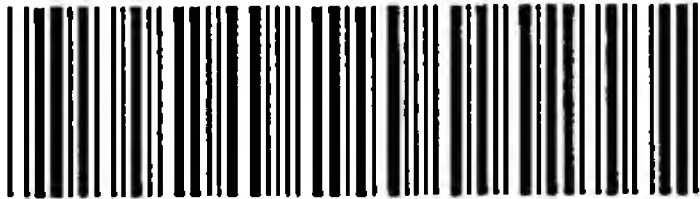


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/605,448	BEYER ET AL.	
	Examiner	Art Unit	
	Dennis Myint	2162	

SEARCHED			
Class	Subclass	Date	Examiner
707	100	8/22/2006	DM
707	1	8/23/2006	DM

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (EPO; JPO; IBM; USPAT)	8/22/2006	DM
EAST (EPO; JPO; IBM; USPAT)	8/23/2006	DM
NPL: ACM	8/22/2006	DM